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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

KOIVUKANGAS et al.

Examiner:

Unassigned

Serial No.:

10/552,403

Group Art Unit:

2829

Filed:

10/07/2005

Docket No.:

KOL.198.WUS

Title:

METHOD AND ARRANGEMENT OF TESTING DEVICE IN MOBILE

**STATION** 

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence and the papers, as described hereinabove, are being deposited in the United States Postal Service, as first class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on May 25, 2006.

**INFORMATION DISCLOSURE STATEMENT (37 C.F.R. §1.97(b))** 

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

With regard to the above-identified application, the items of information listed on the enclosed Form 1449 are brought to the attention of the Examiner.

This statement should be considered because it is submitted either within three months of the filing date or before the first Office Action of the above-identified application. Accordingly, no fee is due for consideration of the items listed on the enclosed Form 1449.

In accordance with 37 C.F.R. §1.98(a)(2), and the 05 August 2003 Official Gazette Notice, only a copy of each foreign document or non-U.S. patent/application listed on the enclosed Form 1449 is provided. One cited document, DE 198 41 470 A1, is a German patent not in the English language. However, pursuant to M.P.E.P. §609, an "X", "Y", or "A" indication may be used to provide the concise explanation of its relevance. Therefore, a counterpart European Search Report including such a relevance indication is provided herewith.

Please note that any notations or markings on the attached documents do not reflect

particular relevance, or lack thereof, to the present application, nor were they necessarily made by

anyone affiliated with the prosecution of the present application.

No representation is made that a reference is "prior art" within the meaning of 35 U.S.C.

§§102 and 103 and Applicants reserve the right, pursuant to 37 C.F.R. §1.131 or otherwise, to

establish that the reference(s) are not "prior art." Moreover, the Applicants do not represent that

a reference has been thoroughly reviewed or that any relevance of any portion of a reference is

intended.

Consideration of the items listed is respectfully requested. Pursuant to the provisions of

M.P.E.P. §609, it is requested that the Examiner return a copy of the attached Form 1449,

marked as being considered and initialed by the Examiner, to the undersigned with the next

official communication.

Respectfully submitted,

HOLLINGSWORTH & FUNK, LLC 8009 34th Avenue South, Suite 125

Minneapolis, MN 55425

952.854.2700

Date: May 25, 2006

By: Lim Michael
Erin M. Nichols

Reg. No. 57,125

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## FORMATION DISCLOSURE STATEMENT

## IN AN APPLICATION

(Use several sheets if necessary)

Docket Number
KOL.198.WUS

Application Number: 10/552,403

Applicant: Koivukangas et al.

Filing Date: 10/07/2005

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				U.S. PATENT DOCUMENT	s			
EXAMINER DOCUMENT NO INITIAL		MENT NO.	DATE	NAME	CLASS	SUBCLASS		G DATE ROPRIATE
	5,481,186 5,889,837 6,118,982 6,404,293		01/02/1996	Heutmaker et al.				
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		<u> </u>	F(	OREIGN PATENT DOCUME	NTS		<u> </u>	
- <i></i>	DOCUMENT NO.		DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	0 525 941		02/03/1993	EP			х	
	0 759 680	A1	02/26/1997	EP			х	
	0 825 734	A2	02/25/1998	EP			х	
	198 41 470 A1 01/63827 A1		04/13/2000	DE				х
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		OTU	ER DOCUMENTS	Moduling Author Title Do	to Portinant Bago	s Eta\		<u> </u>
	1997	Anthony P. Autotestcor XP0102530	Ambler, Moshe I n Proceedings Ah 057 ISBN: 0-780		gar, "Economics of 25 1997, New York	Diagnosis" Autote k, NY USA, IEEE, I	pages 435 – 44	5.
	1999	Yervant Zorian, "Built-In-Self-Test", Microelectronic Engineering, Elsevier Publishers, BV., Amsterdam, NL, Vol. 49, no 2, November 1999, pages 135-138. XP004182057, ISSN: 0167-9317.						
	2001	Louis Y. Ungar et al., "IEEE-1149.X Standards: Achievements vs. Expectations", 2001 IEEE Autotestcon Proceedings. IEEE Systems Readiness Technology Conference. Autotestcon 2001, Valley Forge, PA, Aug. 20-23, 2001, IEEE Autotestcon Proceedings: IEEE Systems Readiness Technology Conference, New York, NY: IEEE, US, Vol. Conf. 37, X 010556098, ISBN: 0-7803-7094-5.						
	2001	Yue-Tsang Chen et al.: "Test Waveform Shaping in Mixed Signal Test Bus by Pre-Equalization", VLSI Test Symposium, 19 <sup>th</sup> IEEE Proceedings on VTS 2001 Apr 29 – 2001 May 3, Piscataway, NJ, USA, IEEE, 29 April 2001 (2001-04-29), pages 260-265, XP010542396 ISBN: 0-7695-1122-8.						
	1994	Lu Y et al.: "Structure and Metrology for a Single-wire Analog Testability Bus", in Proceedings of the International T Conference, Washington, Oct. 2 – 6, 1994, New York, IEEE, US, 2 October 1994 (1994-10-02), pages 919-928, XP000520055 ISBN: 0-7803-2103-0.						

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.